

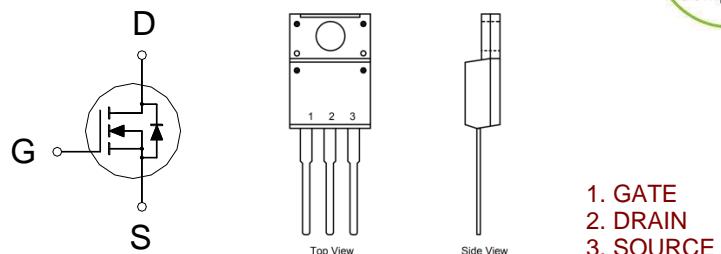
NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P3065JF**

TO-220F

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
650V	115mΩ	30A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	650	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	30	A
$T_C = 100^\circ C$	I_D	19	
Pulsed Drain Current ¹	I_{DM}	60	A
Avalanche Current ³	I_{AS}	4.2	
Avalanche Energy ³	E_{AS}	662	mJ
Power Dissipation	P_D	42	W
$T_C = 100^\circ C$	P_D	17	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	3	62.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.²Ensure that the channel temperature does not exceed 150°C.³ $V_{DD} = 50V$, $L = 75mH$, starting $T_J = 25^\circ C$.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	650			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3.2	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650V, V_{GS} = 0V$			1	
		$V_{DS} = 520V, V_{GS} = 0V, T_J = 100^\circ C$			10	μA
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 15A$		92	115	$m\Omega$
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 15A$		27		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 100V, f = 250KHz$		2287		pF
Output Capacitance	C_{oss}			128		
Reverse Transfer Capacitance	C_{rss}			2.4		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		3.6		Ω
Total Gate Charge ²	Q_g	$V_{DS} = 520V, V_{GS} = 10V, I_D = 15 A$		63		nC
Gate-Source Charge ²	Q_{gs}			13		
Gate-Drain Charge ²	Q_{gd}			26		
Turn-On Delay Time ²	$t_{d(on)}$			42		
Rise Time ²	t_r	$V_{DD} = 325V,$ $I_D \geq 15A, V_{GS} = 10V, R_{GEN} = 25\Omega$		50		nS
Turn-Off Delay Time ²	$t_{d(off)}$			225		
Fall Time ²	t_f			57		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				30	A
Forward Voltage ¹	V_{SD}	$I_F = 30A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 10A, dI_F/dt = 100A/\mu s$		381		nS
Reverse Recovery Charge	Q_{rr}			5.5		uC

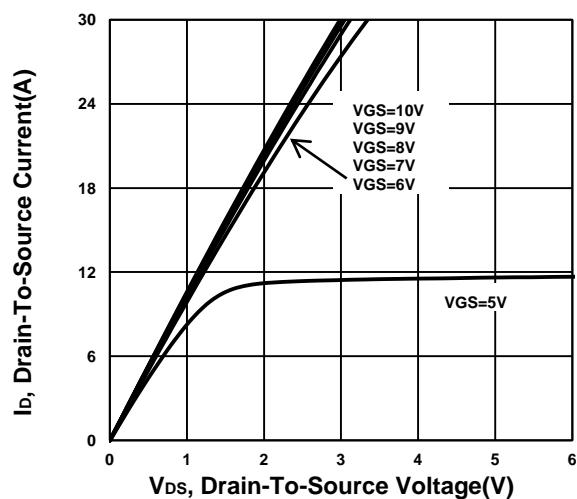
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

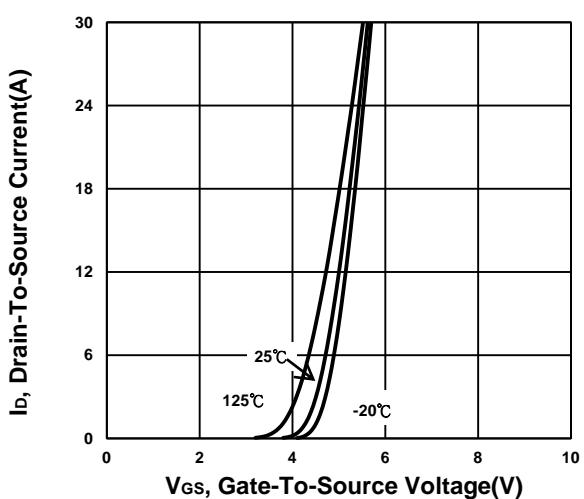
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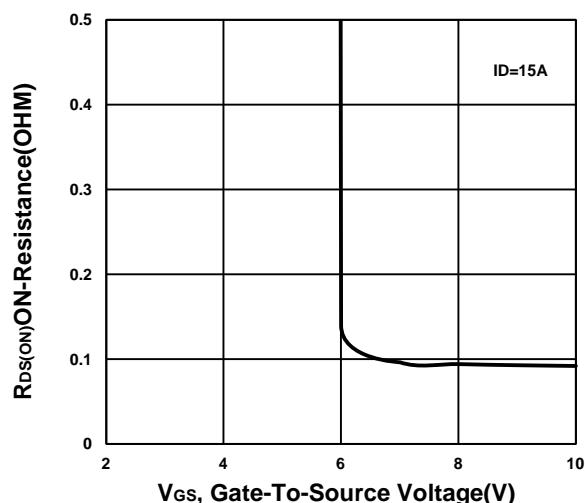
Output Characteristics



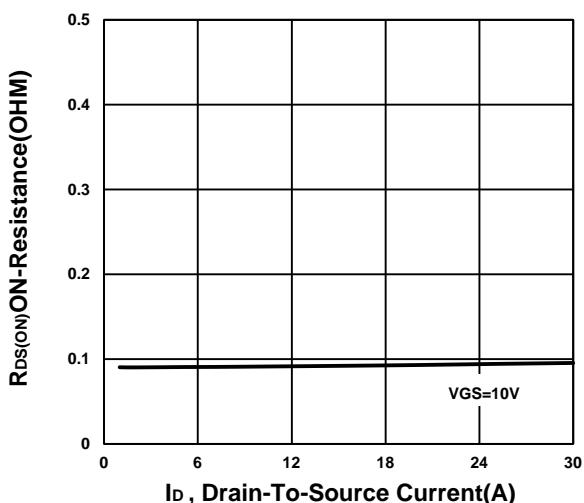
Transfer Characteristics



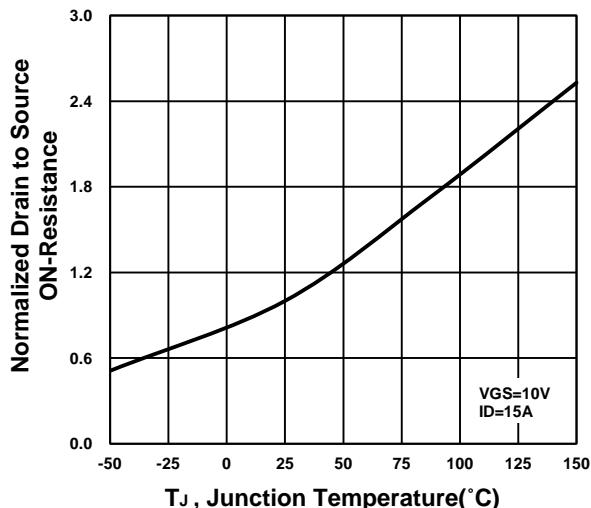
On-Resistance VS Gate-To-Source Voltage



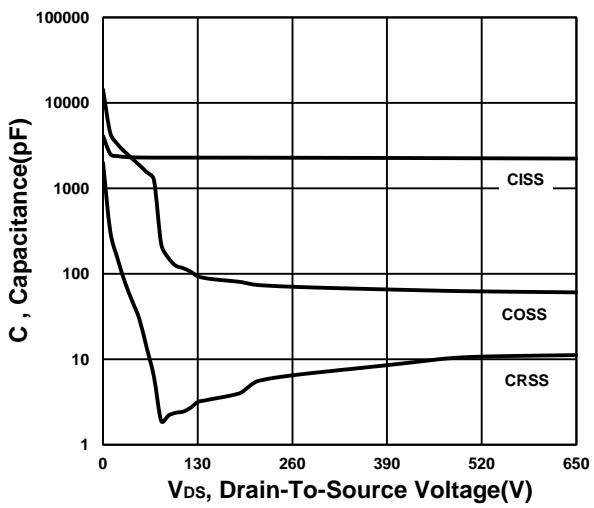
On-Resistance VS Drain Current

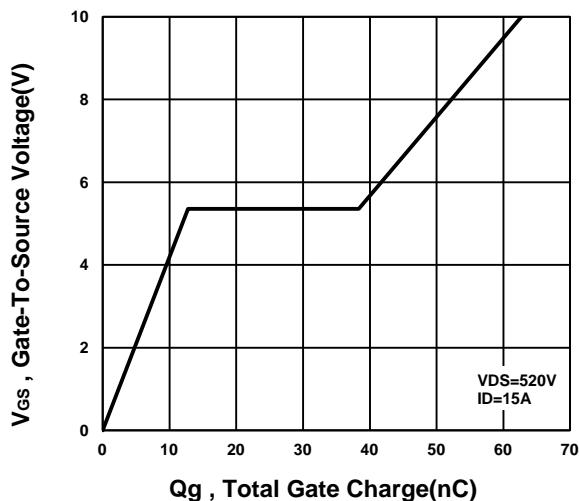
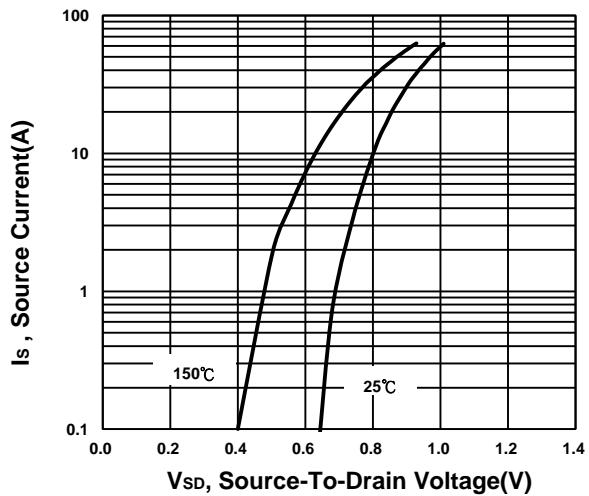
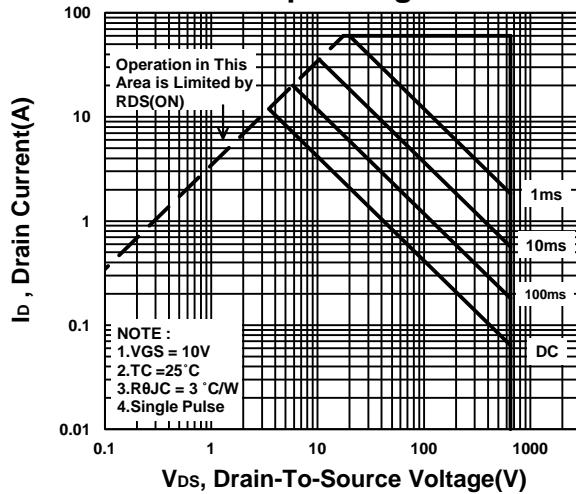
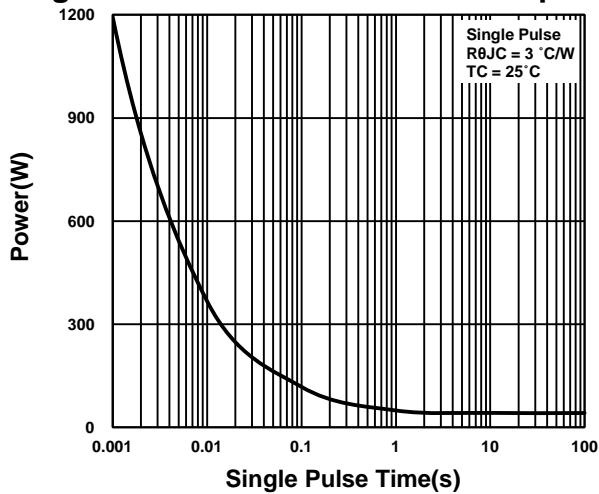


On-Resistance VS Temperature



Capacitance Characteristic



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Halogen-Free & Lead-Free****Gate charge Characteristics****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**